

#### 4.1. RADIATIONS USED IN CRYSTALLOGRAPHY

$\lambda \approx 10^0 \text{ \AA}$ ), protons or ions of elements with quite high atomic number and energy ( $E_k \approx 10^3 - 10^6 \text{ eV}$ ) are also used in scattering, channelling or shadowing experiments (see Section 4.1.5).

#### 4.1.3. Most frequently used radiations

Average diffraction properties of X-rays, high-energy electrons, and neutrons are listed in Table 4.1.3.1. They can be varied with respect to the material analysed by changing the incident-beam operating conditions and they also greatly depend on the mutual interaction of radiation with the material. The values presented are typical rather than extreme ones and should be used as a guide for rough estimates and for general orientation in the subject. Details are given in the following sections. The properties of the radiations and the features of their interaction with crystals also impose limitations on the sample choice or preparation, on the recording of the diffraction data, and on the theoretical interpretation of these data. The different nature of the scattering of X-rays and electrons (interacting with the electron-density distribution or with the potential distribution) and neutrons (which are mainly scattered by nuclei) may be used in combined experiments to study details of thermal smearing of atomic positions and bonding characteristics of the electron-density distribution.

#### Notes to Table 4.1.3.1

(1) *Charge*. Charged electrons interact strongly with matter and must be used in vacuum whereas X-rays and neutrons can be used in air.

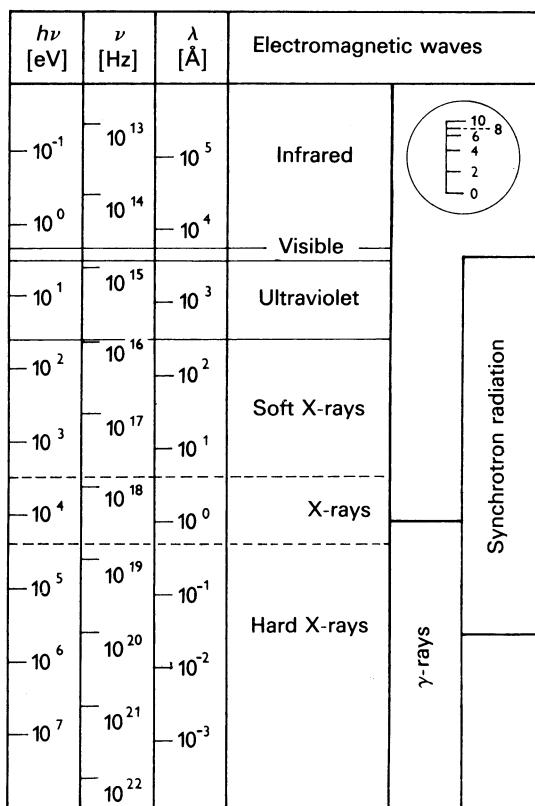


Fig. 4.1.2.1. Comparison of the energy, frequency, and wavelength of the electromagnetic waves used in crystallography (logarithmic scale).

Table 4.1.3.1. Average diffraction properties of X-rays, electrons, and neutrons

|   | X-rays  | Electrons                                       | Neutrons  |
|---|---|---|---|
| (1) Charge                                      | 0   | $-1 \text{ e}$                                  | 0   |
| (2) Rest mass                                   | 0   | $9.11 \times 10^{-31} \text{ kg}$               | $1.67 \times 10^{-27} \text{ kg}$               |
| (3) Energy                                      | 10 keV  | 100 keV   | 0.03 eV   |
| (4) Wavelength                                  | 1.5 Å   | 0.04 Å  | 1.2 Å   |
| (5) Bragg angles                                | Large   | 1°  | Large   |
| (6) Extinction length                           | 10 μm   | 0.03 μm   | 100 μm  |
| (7) Absorption length                           | 100 μm  | 1 μm  | 5 cm  |
| (8) Width of rocking curve                      | 5"  | 0.6°  | 0.5"  |
| (9) Refractive index<br>$n = 1 + \delta$        | $n < 1$   | $n > 1$   | $n \leq 1$                                      |
| (10) Atomic scattering amplitudes $f$           | $10^{-3} \text{ \AA}$                           | $10 \text{ \AA}$                                | $\pm 1 \times 10^{-6}$<br>$10^{-4} \text{ \AA}$ |
| (11) Dependence of $f$ on the atomic number $Z$ | $\sim Z$  | $\sim Z^{2/3}$                                  | Nonmonotonic                                    |
| (12) Anomalous dispersion                       | Common  | -   | Rare  |
| (13) Spectral breadth                           | 1 eV<br>$\Delta\lambda/\lambda \approx 10^{-4}$ | 3 eV<br>$\Delta\lambda/\lambda \approx 10^{-5}$ | 500 eV<br>$\Delta\lambda/\lambda \approx 2$     |

(2) *Rest mass*. The wavelength of moving particles with the same energy is inversely proportional to the square root of their mass.

(3) *Energy*: Energies of X-rays generated in commonly used X-ray tubes range from 5 to 17 keV. High-energy electrons used in electron microscopes have energies from 40 to 300 keV, but energies of 1 MeV or more are achievable (for low-energy electrons, see Subsection 4.1.4.2). The extremely low energy of neutrons as compared with X-rays or electrons leads to their strong inelastic interaction with phonons (see Subsection 4.1.4.3).

(4) *Wavelength*. The radius of the Ewald sphere for electrons is much larger than that for X-rays or neutrons and thus part of the reciprocal-lattice plane image can be seen immediately if fixed-crystal electron diffraction is used. Wavelengths of electrons and neutrons are tunable by changing instrumental conditions (high voltage in the microscope and the temperature inside the reactor, respectively) whereas X-ray wavelengths are given by discrete lines of the characteristic spectra of the X-ray tube targets (for other X-ray sources, see Subsection 4.1.4.1).

(5) *Bragg angles*. The whole observable diffraction pattern obtained by electrons is contracted into small angles not exceeding 3–5° with the primary beam.

(6) *Extinction length*. The extinction length corresponds to the thickness of the crystal required for the whole incident beam to be scattered into the Bragg reflected beam and then to be scattered back into the direction of the incident beam. If the size of a nearly perfect crystal (or the size of the mosaic blocks) is comparable to or exceeds the extinction length for the given reflection then the dynamic diffraction theory (or the primary-extinction correction of applied kinematic theory in